

Notice of References Cited

Application/Control No.

10/691,172

Applicant(s)/Patent Under
Reexamination
YAO ET AL.

Examiner

Paul D. Kim

Art Unit

3729

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,342,715	01-2002	Shimizu et al.	257/314
	B	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"Design and performance of an inductive current probe for integration into the trace suspension assembly"; Kos, A.B.; Silva, T.J.; Kabos, P.; Pufall, M.R.; DeGroot, D.C.; Webb, L.; Even, M.; Magnetics, IEEE Transactions on Volume 38; Jan. 2002; Pages:50 - 54.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.